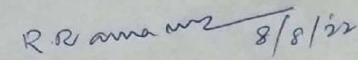


CERTIFICATE

This is to certify that the work entitled "*XRD profile fitting and analysis of Fe thin film*" is being submitted by **S. Suryakumar (III yr B.Sc)** partial fulfillment of the requirement for the award of the degree of **B Sc Physics** at Sathyabama Institute of Science and Technology, Chennai is an authentic record of her work carried out during the period from 18 July to 05 August, under the supervision and guidance of Dr. R. Ramaseshan, SO/G, Head SSS, SND, MSG, IGCAR, Kalpakkam.

This is to certify that the above statement made by the candidate is correct to the best of my / our knowledge.

 8/8/22

Signature of the Supervisor

[R.Ramaseshan]

Dr. R. Ramaseshan
Scientific Officer (G)
Surface Science Section
Surface and Nanoscience Division
Indira Gandhi Centre for Atomic Research
Kalpakkam -603 102, TN, INDIA